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Power and Charge Deposition in Multilayer Dielectrics undergoing **Monoenergetic Electron Bombardment**

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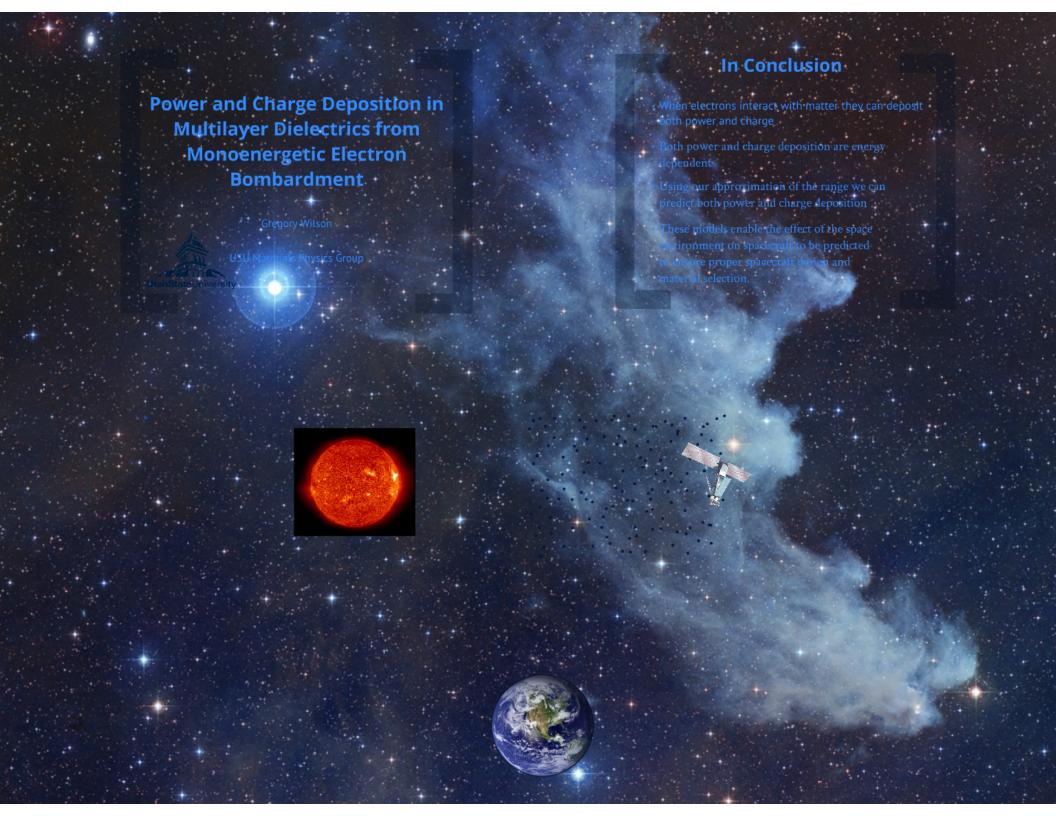
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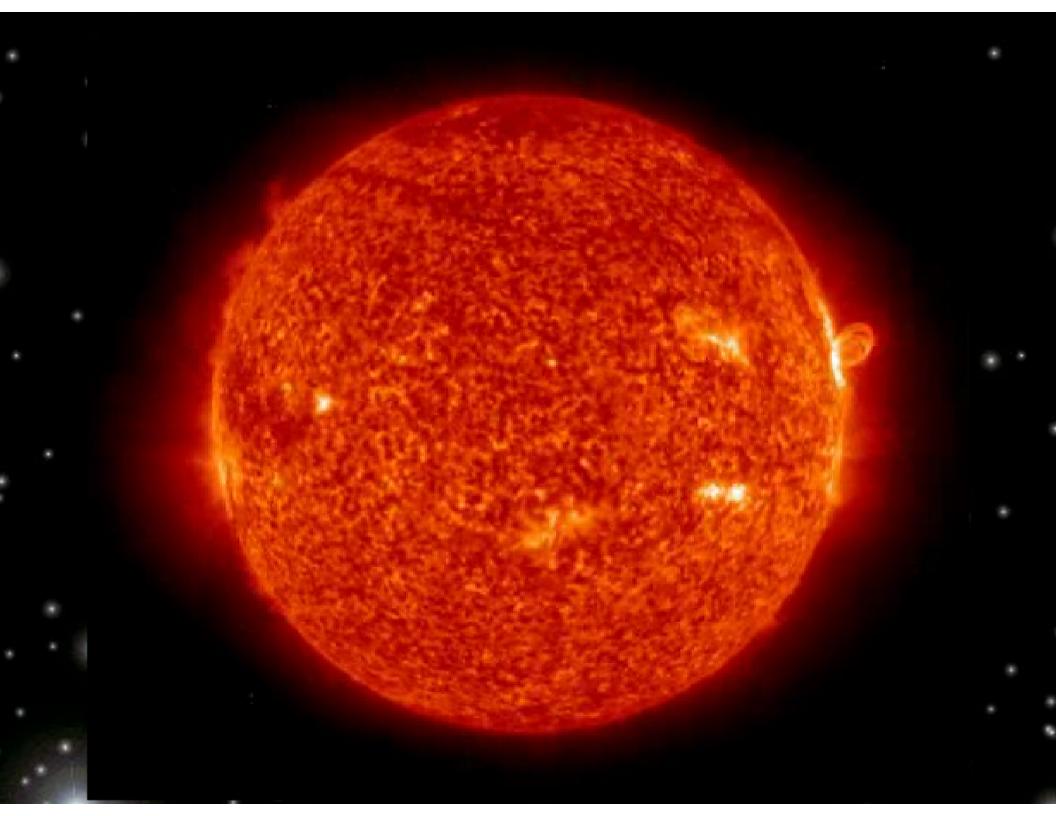
Power and Charge Deposition in Multilayer Dielectrics from Monoenergetic Electron Bombardment

Gregory Wilson



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Power Deposition vs Charge Deposition

- As electrons penetrate a
 material they impart energy
 to the material through
 several inelastic collisions
- When the electron's

 Kinetic energy is depleted it
 deposits it's charge at the
 range R(E_b) where E_b is the
 incident energy of the
 electron.

Continuous Slow Down Approximation

- In the CSDA, the rate of energy loss, dE/dz (or total stopping power, S), at every position along the penetration path is assumed constant
- For a given incident energy, E_b , the CSDA range is obtained by integrating the total stopping power over the full penetration depth

$$\frac{dE}{dz} \equiv S_{CSDA}(E_b) = \frac{E_b}{R} = \frac{\overline{E}}{\lambda} = \frac{E_{min}}{\lambda_{min}}$$

Stopping Power

Total Energy over Total Range

Mean Energy loss over IMFP

Minimum Energy Loss over Minimum IMFP

Electron Range

High Energy

$$\boldsymbol{b} \; \boldsymbol{E}_{\boldsymbol{b}}^{n} \; \left[1 - \left[1 + \left(\frac{E_{\boldsymbol{b}}/N_{\boldsymbol{V}}}{m_{\boldsymbol{e}}c^2} \right) \right]^{-2} \right]$$

Power law

Relativistic factor

Mid Energy

$$\left[\frac{E_b}{\overline{E}}\right] \lambda_{IMFP}(E_b) \left(1 - e^{-E_b/\overline{E}}\right)^{-1}$$

of collisions

of IMFPs that occur The likelihood of a collision (~1)

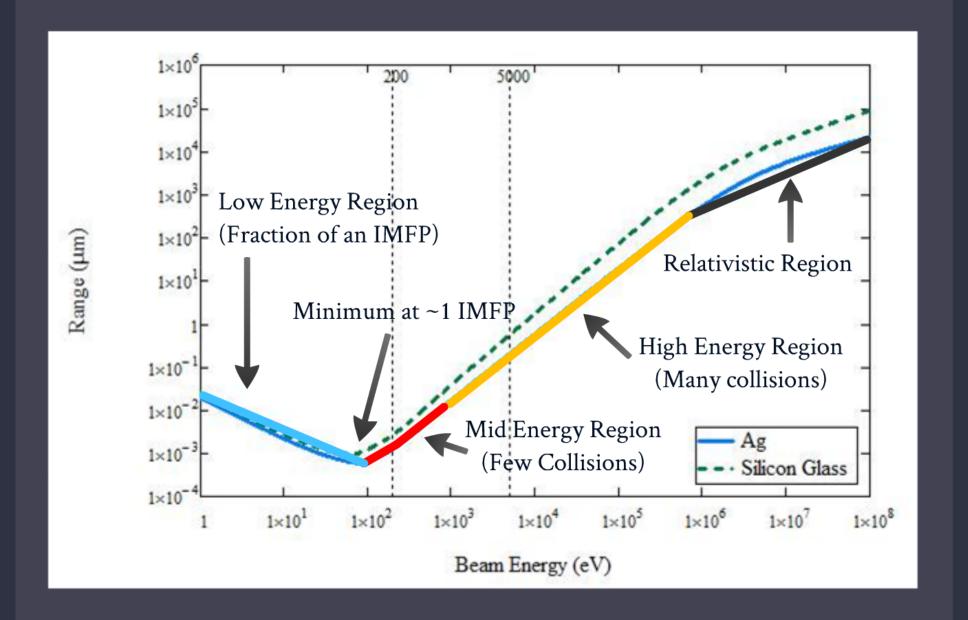
Low Energy

$$\left[\frac{E_b}{\overline{E}}\right] \left[\lambda_{IMFP} \left(\overline{E}\right) \frac{\left(1 - e^{-E/E}\right)}{\left(1 - e^{-E_b/\overline{E}}\right)}\right] \left(1 - e^{-E_b/\overline{E}}\right)^{-1}$$

of collisions

Fraction of IMFPs that occur The likelihood of a collision (<1)

Electron Range



Dose Rate

• The dose rate in a homogeneous material is approximately inversely proportional to the volume in which radiation energy is deposited.

$$D(\dot{E}_b) \equiv \frac{\partial D}{\partial t} = \frac{E_b J_b}{\rho_m R(E_b) q_e} \propto \frac{E_b}{R(E_b)}$$

 To calculate the deposited power for each layer we can multiply the dose rate by the amount of material radiated

Power Deposition

• First Layer: R(Eb) < d

$$P(E_b) = \frac{E_b J_b A}{q_e}$$

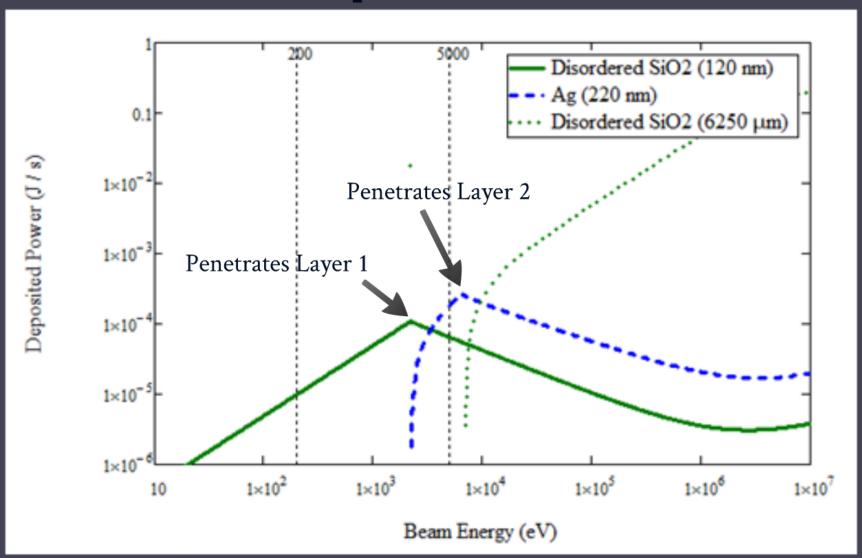
• First Layer: R(Eb) > d

$$P(E_b) = \frac{E_b J_b A}{q_e} \frac{d}{R(E_b)}$$

Subsequent Layers

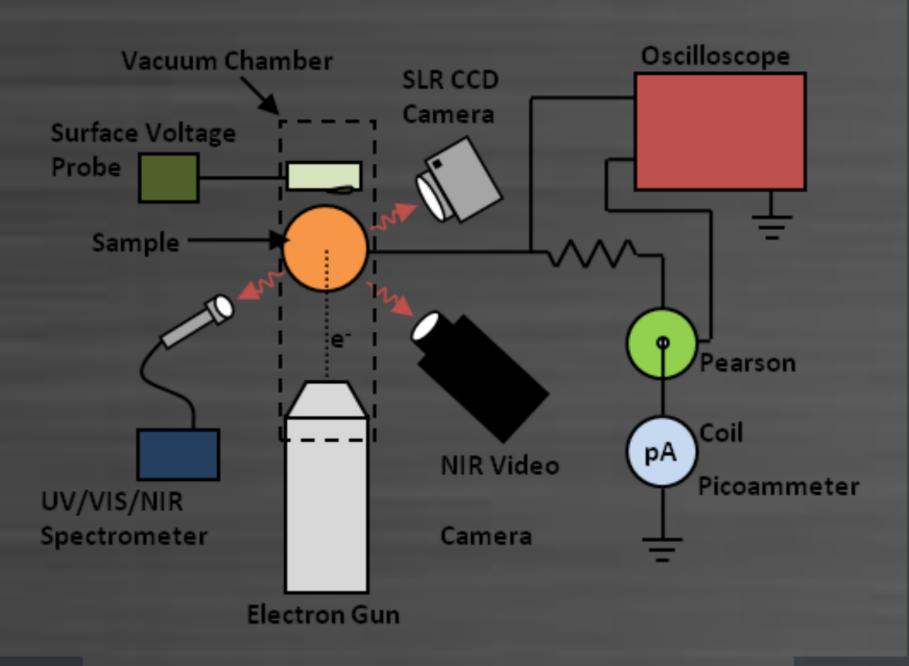
The equations are the same for all subsequent layers but you must scale E_b as the energy at which the electrons enter that particular layer

Multilayer Power Deposition





Experimental Setup



Experiment Parameters

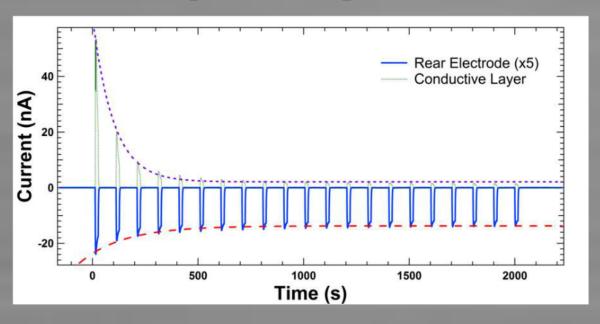
Charge Deposition

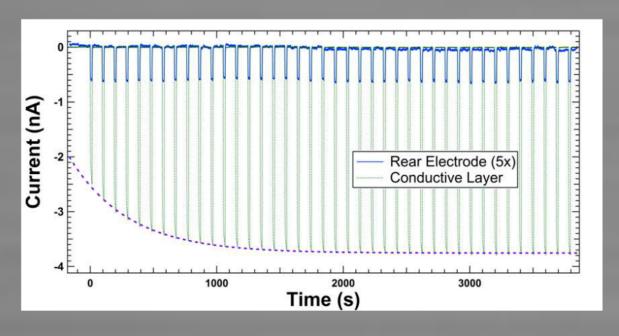
Multilayer SiO₂ (120 nm SiO₂, 220 nm Ag, 0.625 cm SiO₂) 15 s pulses at 2 nA/cm² to 20 nA/cm² flux densities Beam energies of 200 eV and 5 keV

Power Deposition

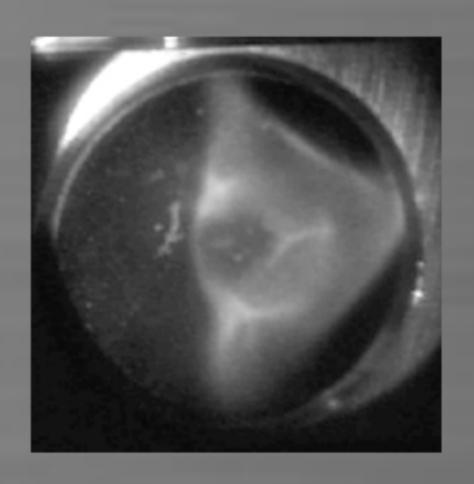
Multilayer SiO₂ (~65 nm SiO₂, 220 nm Au, 0.625 cm SiO₂) 15 s pulses at 2 nA/cm² to 100 nA/cm² flux densities Beam energies of 5 keV to 25 keV

Charge Deposition



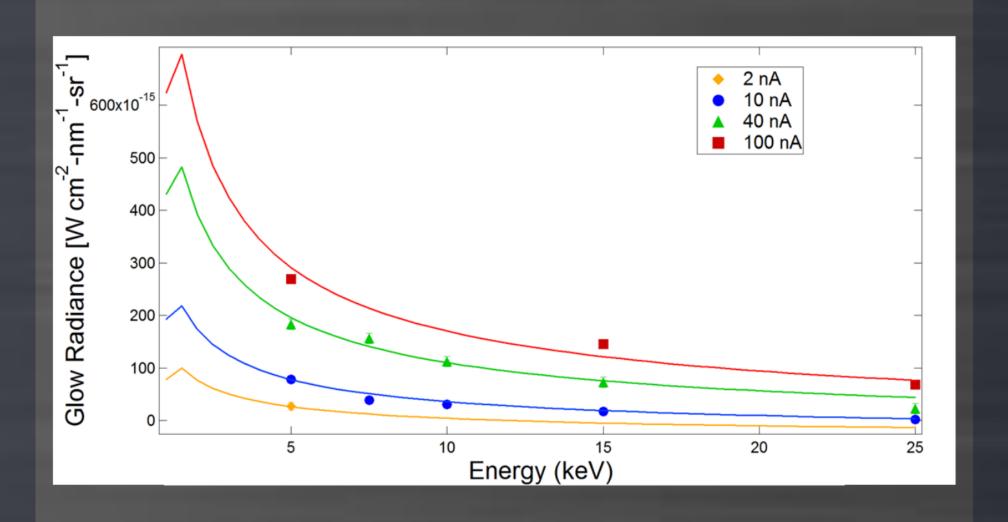


Power Deposition



Disordered, thin-films of fused silica undergoing electron beam irradiation have been shown to produce a lowefficiency cathodoluminescence

Power Deposition



In Conclusion

- When electrons interact with matter they can deposit both power and charge
- Both power and charge deposition are energy dependent
- Using our approximation of the range we can predict both power and charge deposition
- These models enable the effect of the space environment on spacecraft to be predicted to ensure proper spacecraft design and material selection.

